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5G and mm-wave Test Challenges

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Challenges of Over The Air (OTA) Testing with ATE

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Shanghai - October 29, 2019





Universität Stuttgart

5G and mm-wave Test Challenges

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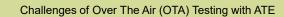
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ATE Challenges for 5G Applications

- 5G is seen as the next major driver of mobile applications
- But 5G presents significant new challenges for ATE:
 - Frequency range from 24 GHz to 44 GHz (might change!!)
 - Modulation frequencies in the range of 800 MHz

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- Devices with antennas integrated in package require over the air (OTA) testing at packaged level
- Silicon vendors would like to keep the testing infrastructure modifications as small as possible
- Costs of test is critical for 5G applications



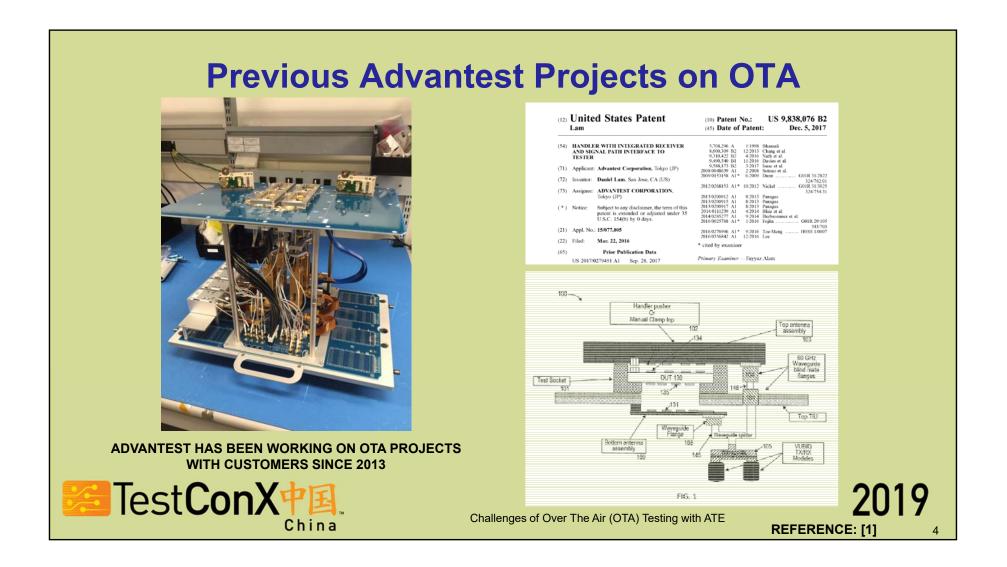
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5G and mm-wave Test Challenges

Current OTA ATE Measurement Approaches

Anechoic Chamber

- Far Field Measurement
- Closer to System Level Test (SLT) than classic RF ATE.
- Integration on a standard ATE production test cell very challenging.
- Test Time?

OTA Single Measurement Antenna Socket

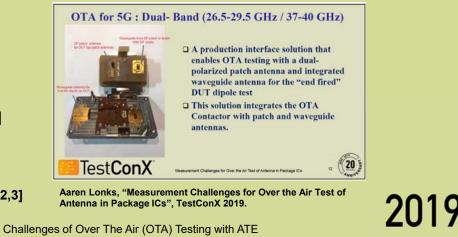
- Measurement Antenna very close to DUT (usually in the radiating near field region).
- Easier integration on current ATE Test Cell environment.

China

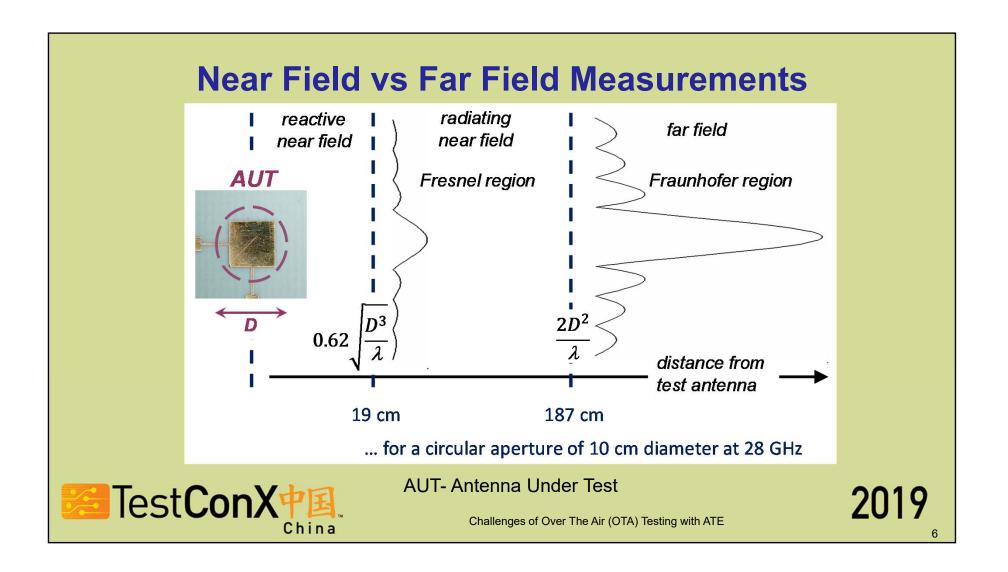
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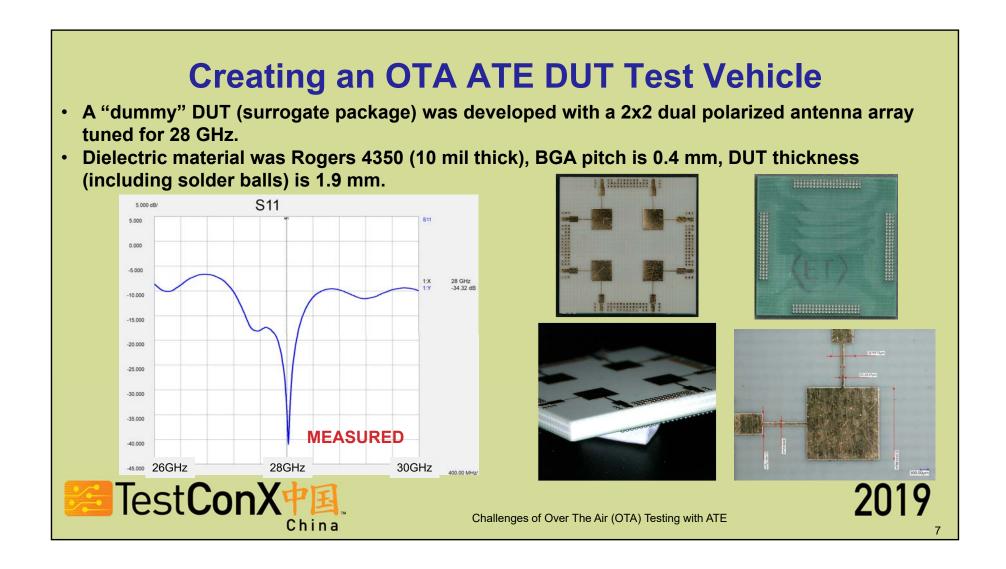
Harrison Chang et al., "From Assembly to Testing, Characterization of Low Cost Organic Substrate for mm-Wave AiP Application", IEEE IMS 2019.



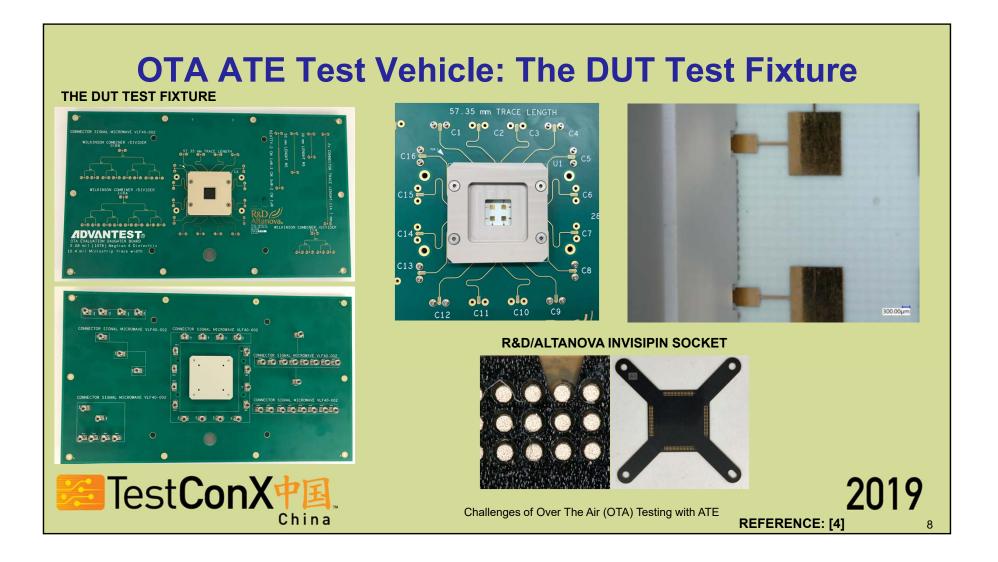
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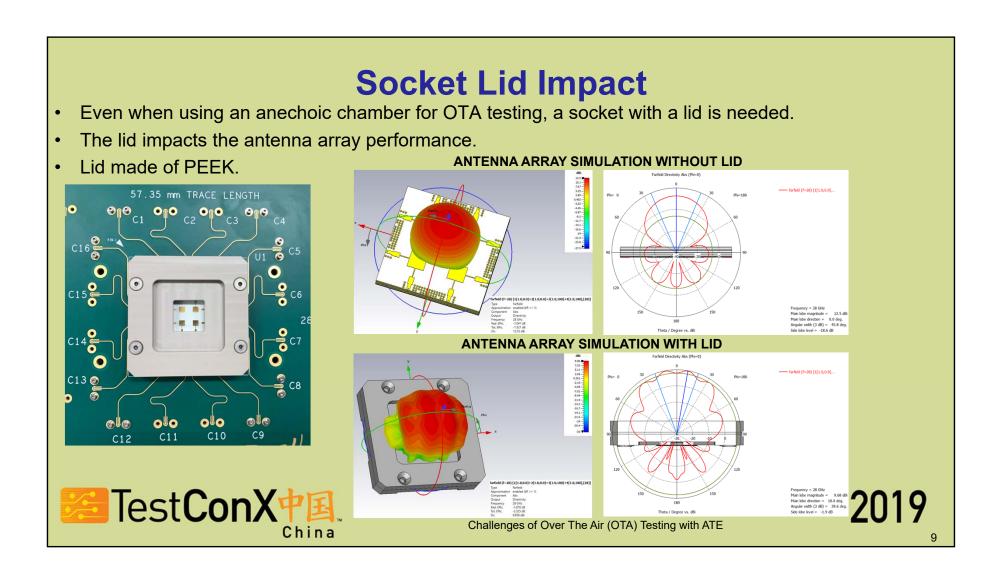


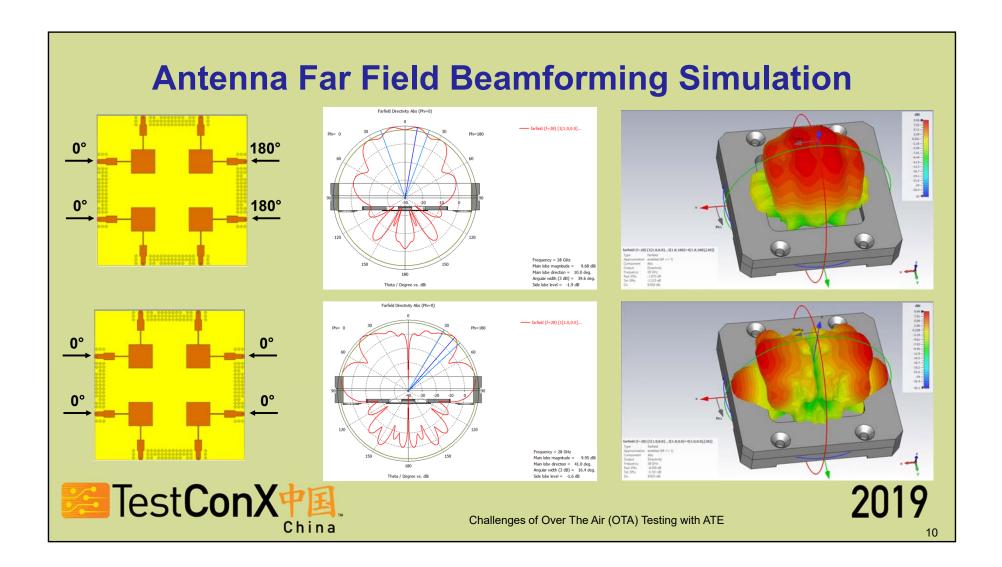
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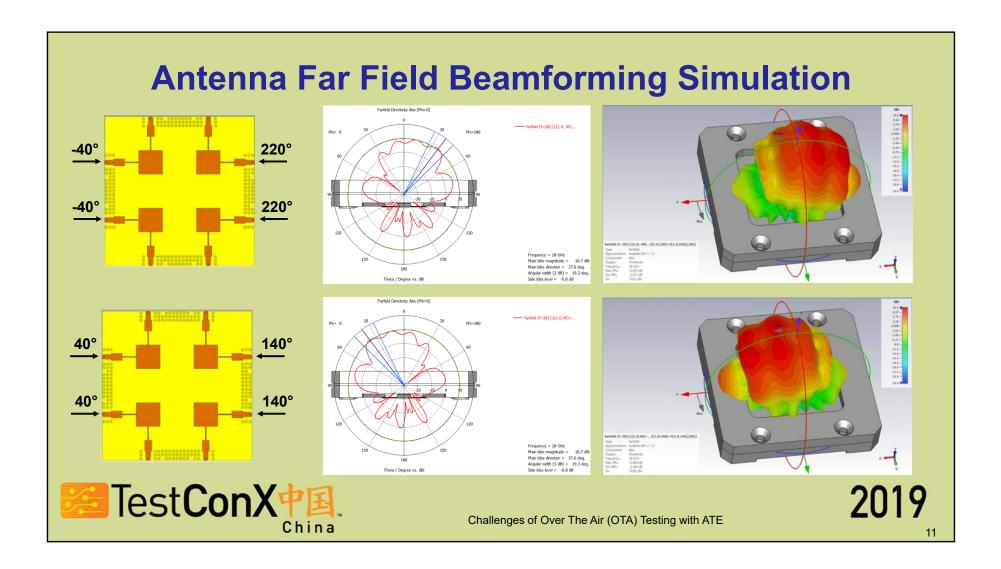


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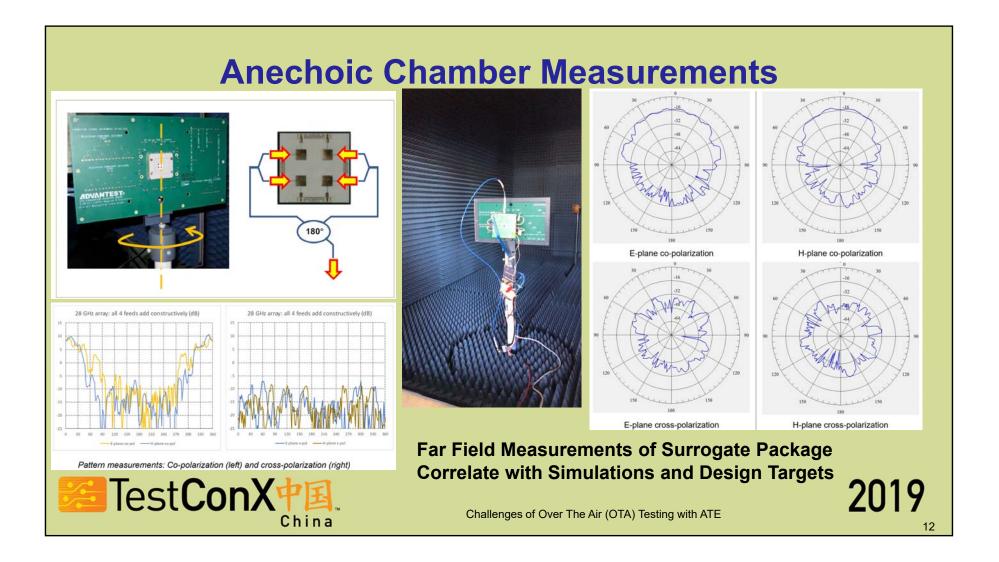




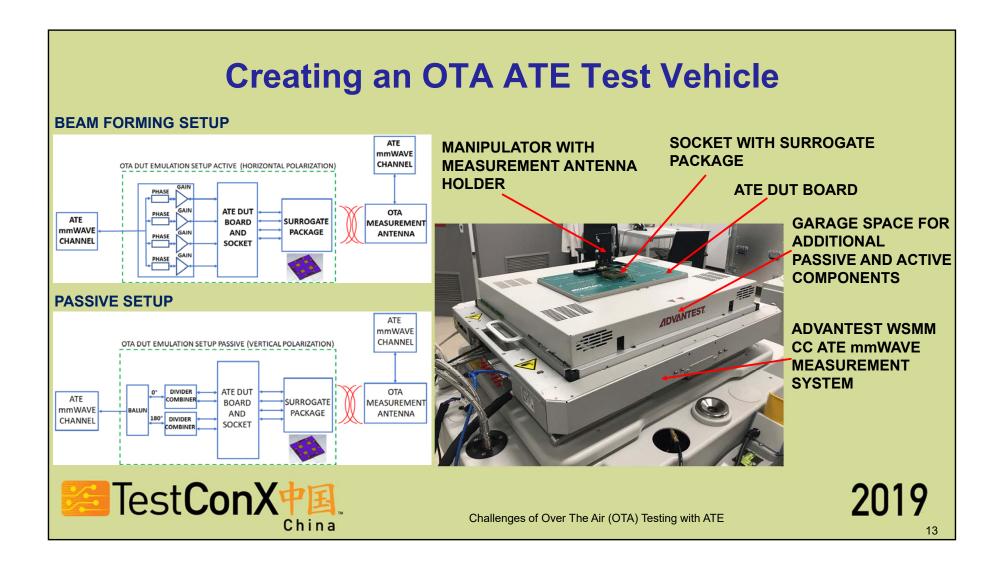




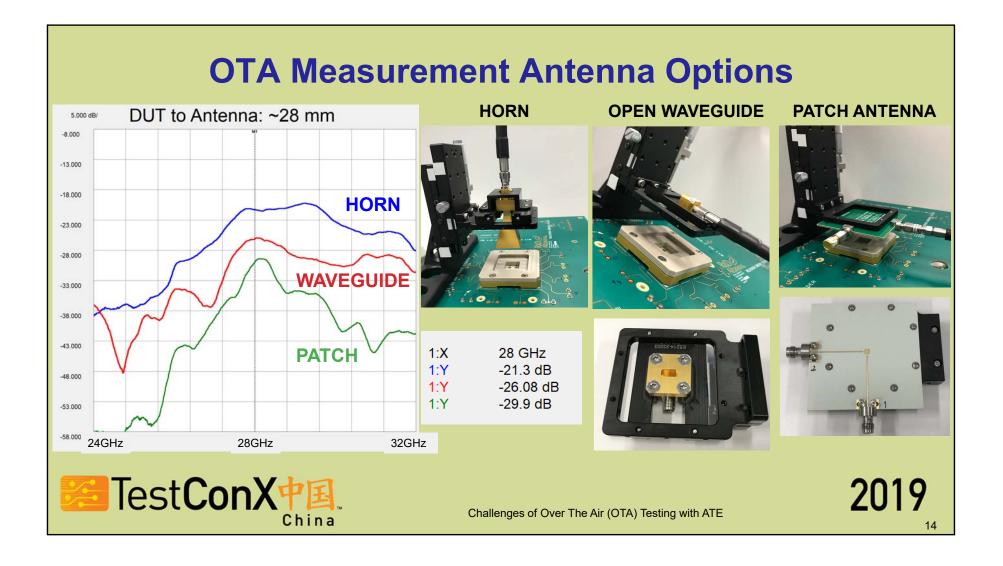
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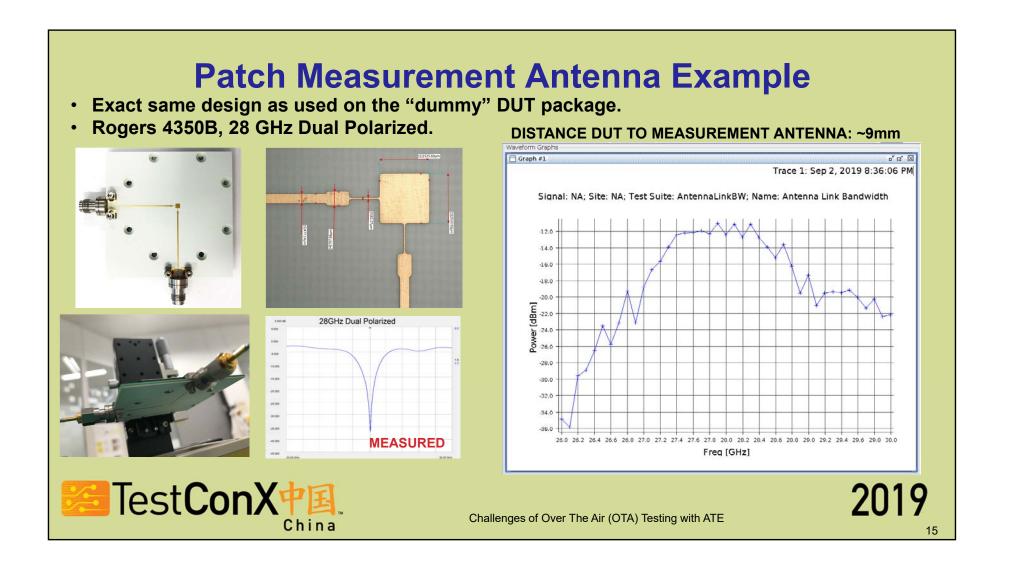
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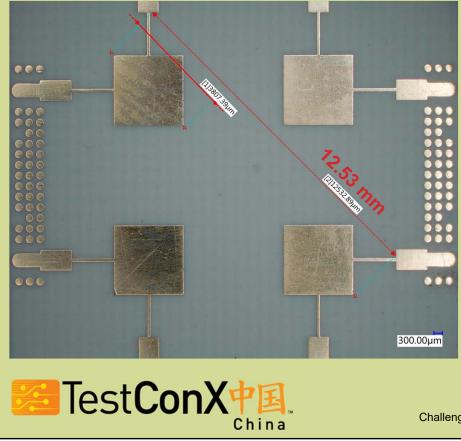


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5G and mm-wave Test Challenges

Computing the Far-Field Distance



 $\lambda_0 \approx \frac{300}{F_{(GHZ)} \times \sqrt{\varepsilon_R}} (mm)$

$$\lambda_0(28 GHz) = 10.71 \text{ mm}$$

ANTENNA ARRAY
Far-Field
$$\approx \frac{2 \times D^2}{\lambda_{0(28 \ GHz)}} \approx \frac{2 \times (13)^2}{10.71} \approx 32 \text{ mm}$$

SINGLE ANTENNA Far-Field $\approx \frac{2 \times D^2}{\lambda_{0(28 \ GHz)}} \approx \frac{2 \times (4)^2}{10.71} \approx 3 \text{ mm}$

... though this is not a useful distance as any (conventional) probe antenna will strongly de-tune the patch feed impedance, leading to (potentially non-linear) variation of transceiver characteristics 2019

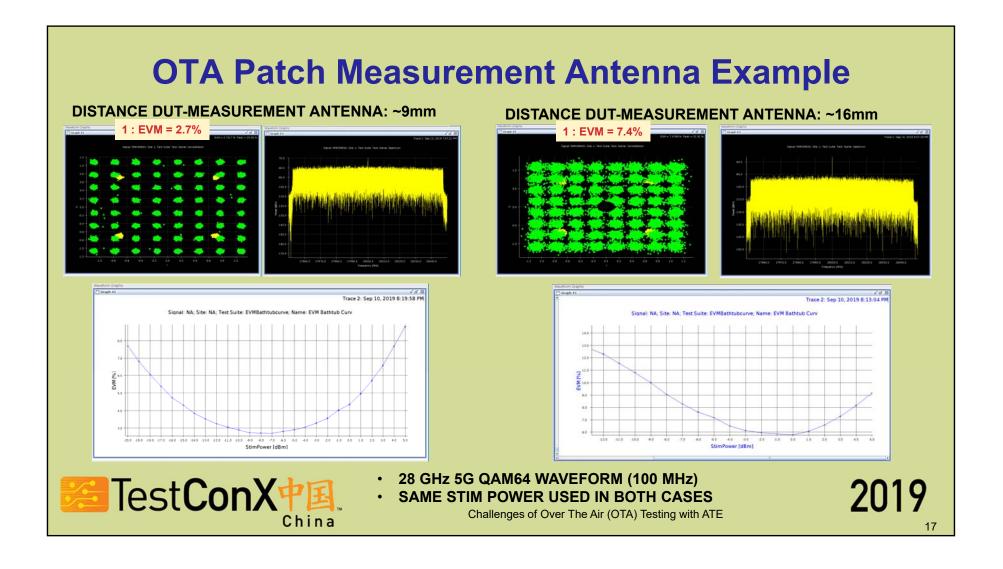
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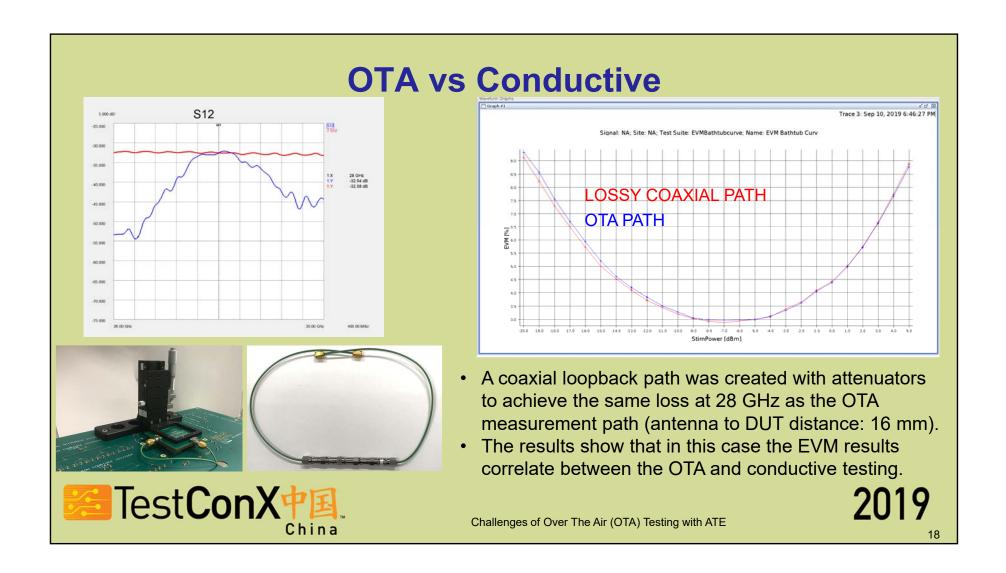
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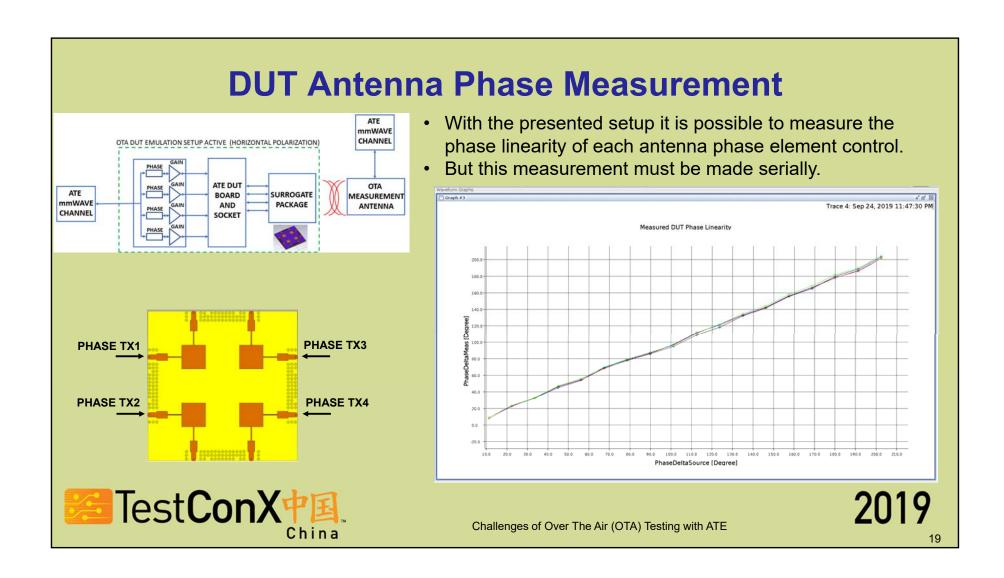
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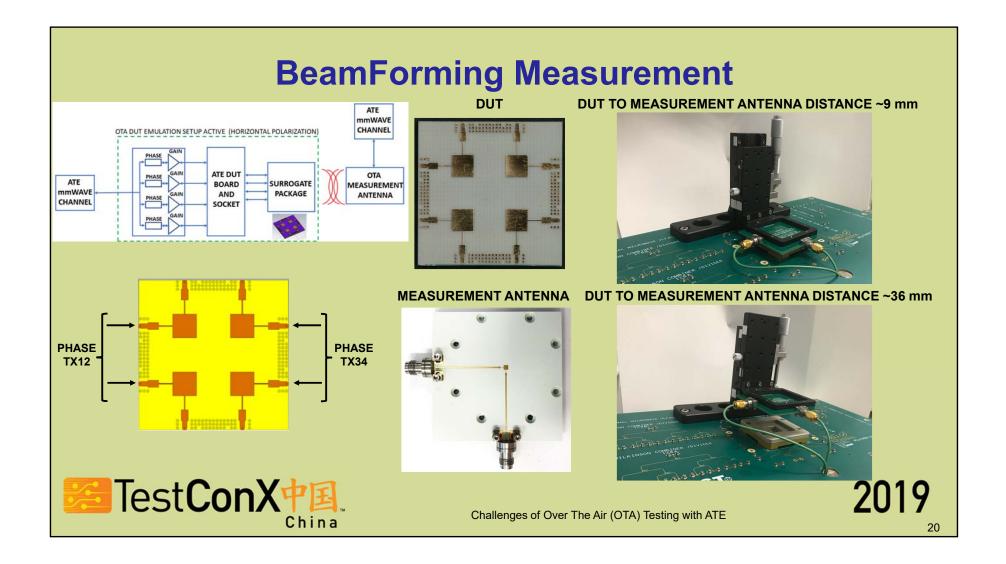




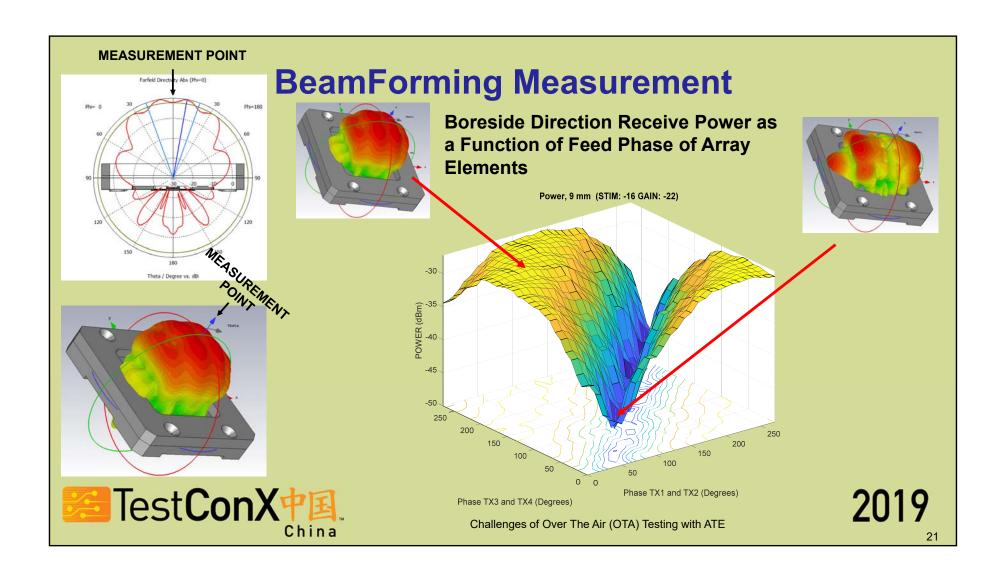


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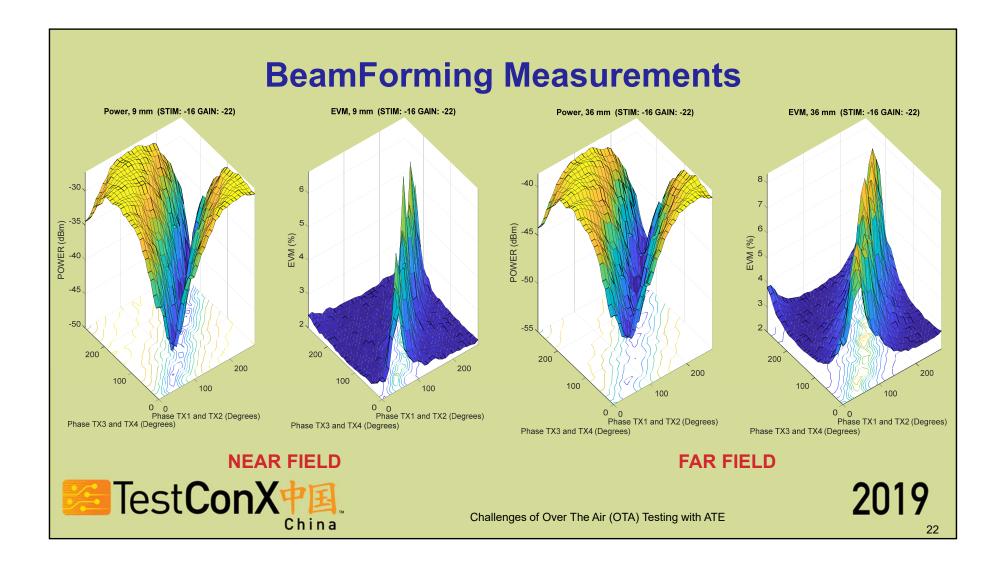


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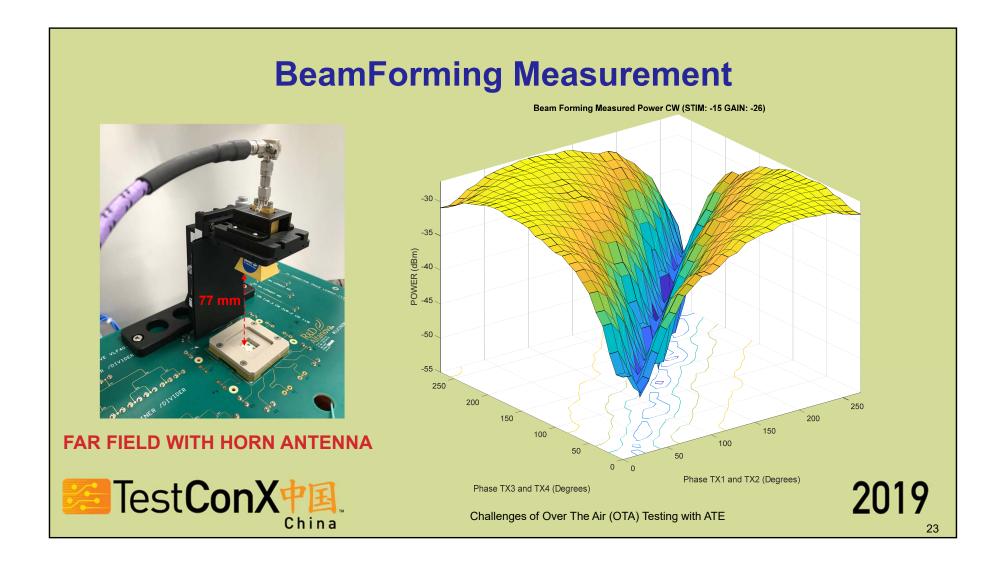
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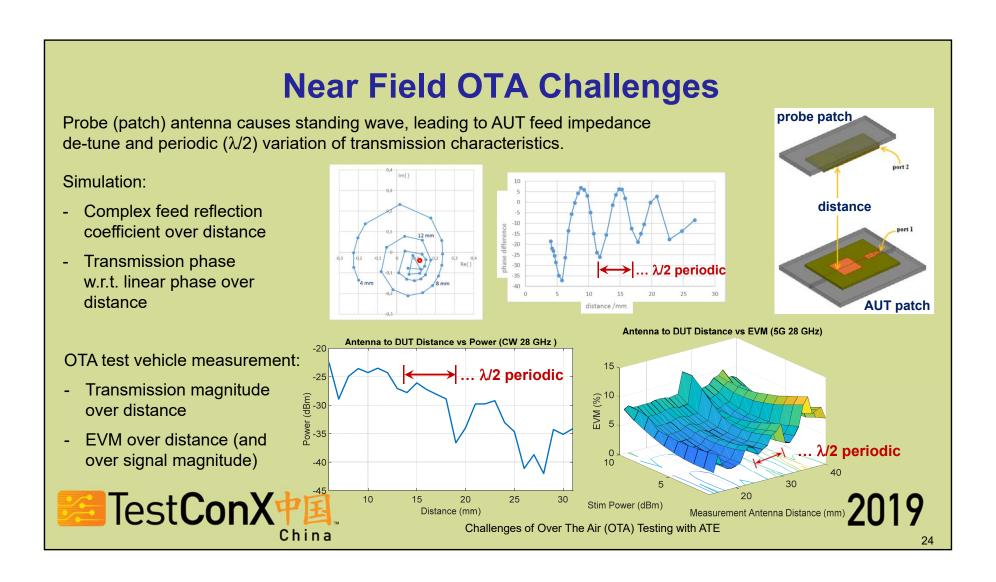
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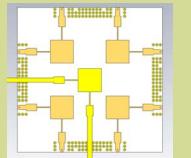


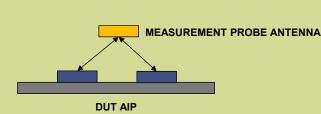


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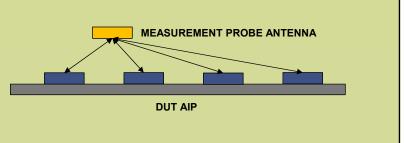


- The presented DUT antenna array and measurement antenna have a symmetric configuration
- This setup gives a too optimistic result because the measurement antenna distance to each DUT array antenna is the same.





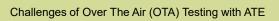
 Any realistic application will have varying distances to different array elements, leading to the test of some elements to fail because of standing wave pattern resp. resonances between array and probe.



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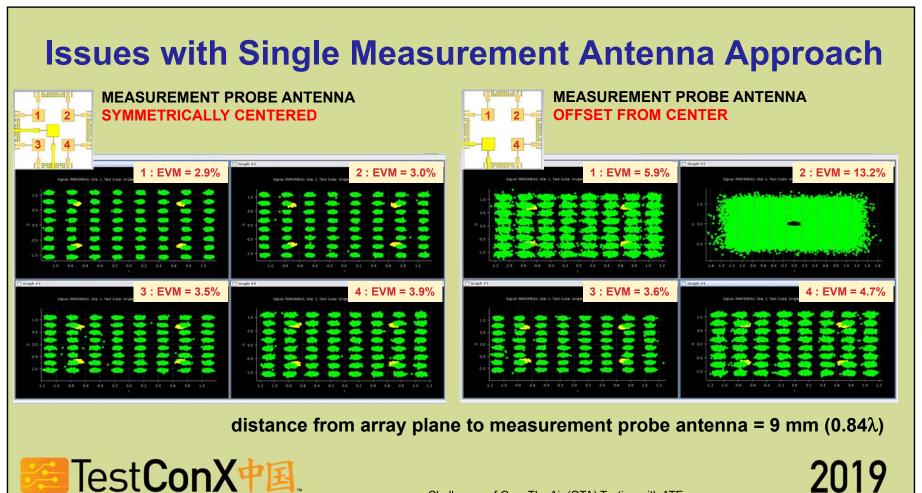
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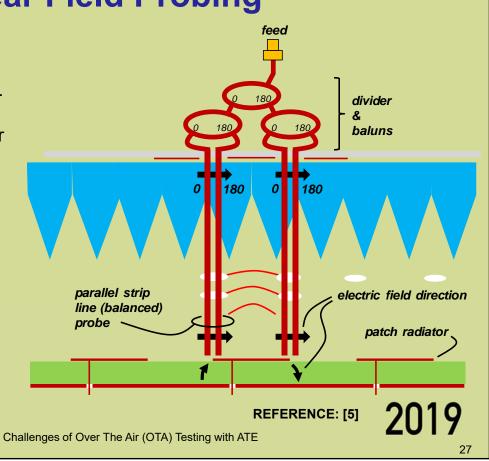
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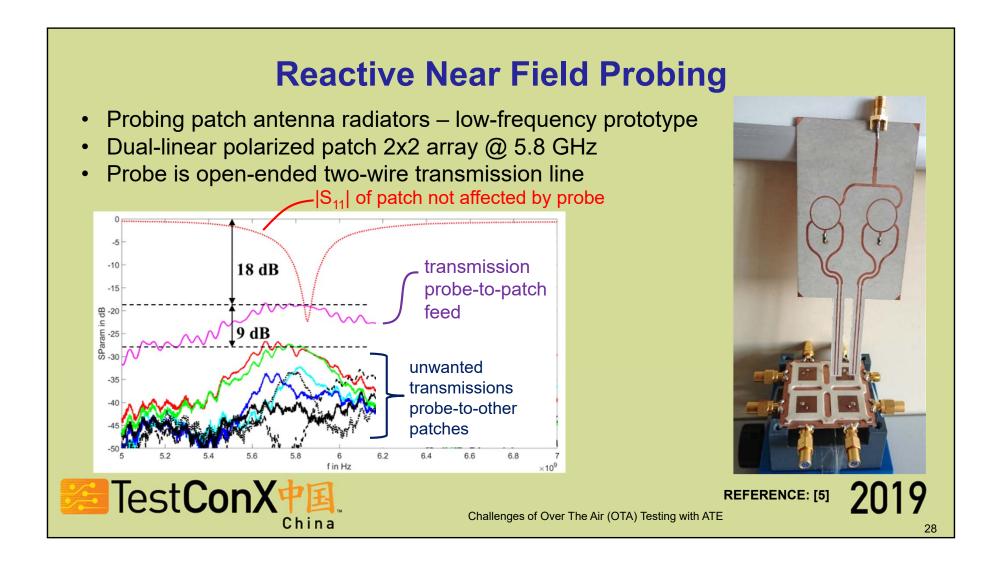
Reactive Near Field Probing

- Probing the radiation of a single radiator of an antenna array by means of a wire-probe pointing into the reactive field of the radiator.
- The wire-probe should not affect the radiator (i.e., radiator feed impedance left unchanged).
- The wire-probe must collect only small part of the electromagnetic field.
- The wire-probe should be routed such that radiated fields are not affected (E must be perpendicular to the wires etc.).

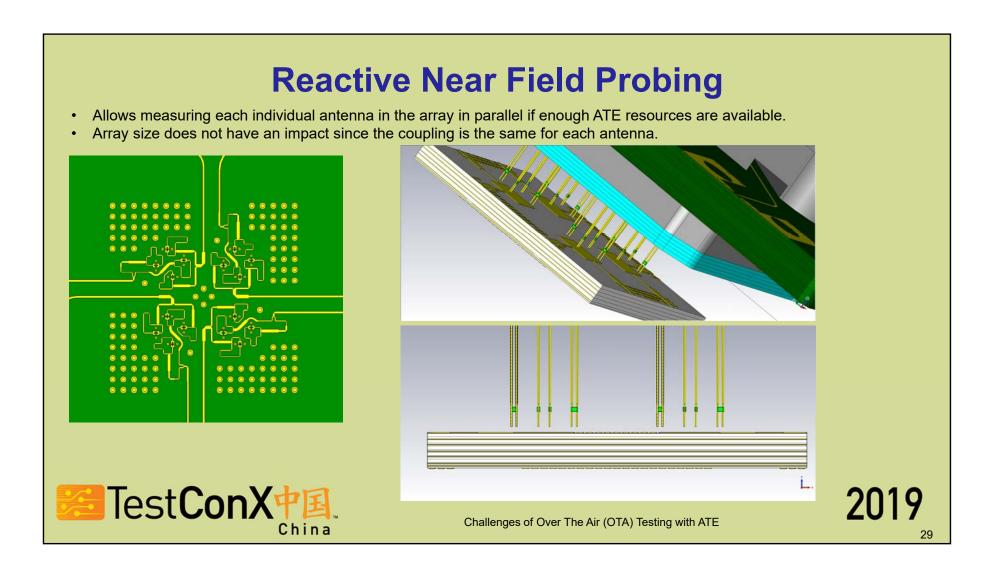
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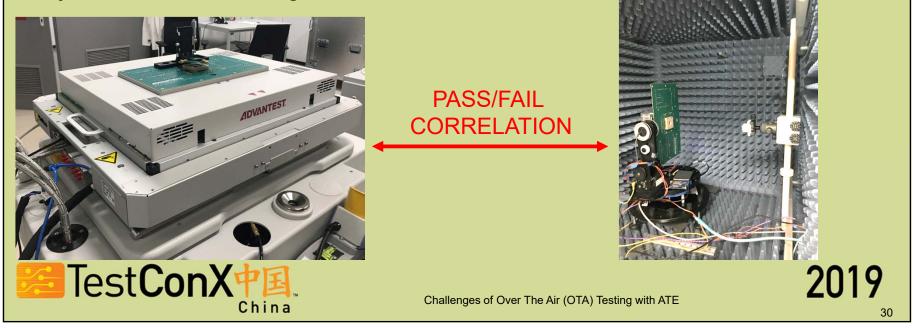
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Evaluation Approach

- The presented evaluation setup provides a pragmatic approach to test different OTA approaches to test a DUT with AIP and correlating with anechoic chamber measurements.
- Can be used with a pre-existing evaluation board for anechoic chamber characterization.
- After a given OTA methodology is evaluated and chosen, the remaining implementation is just a mechanical challenge.



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Conclusions

- If a near field OTA strategy is chosen it is important to understand its limitations.
- A new OTA approach based on probing the reactive near field was presented that addresses some of the near field OTA limitations.
- The presented ATE OTA setup allows to easy evaluation of different OTA measurement approaches with different geometries.
- After verifying that the chosen OTA test methodology works and has the needed failure coverage, it then becomes only a mechanical problem to implement it in a productive solution for a high-volume ATE test cell.



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